



Granice Metod Optycznych: Nano-Karakterystyka i Koherentna Kontrola

Indeks: 827552 Producent: Springer Kod producenta: 9783662507315

Cena: 514.58 zł

Opis

Frontiers in Optical Methods: Nano-Characterization and Coherent Control (Springer Series in Optical Sciences, Band 180)

Producent: Springer

- **temat:** Atomic & molecular physics, Electronics engineering, Laser physics, Nanotechnology, Spectrum analysis, spectrochemistry, mass spectrometry, SCIENCE / Chemistry / Physical & Theoretical, SCIENCE / Nanoscience, SCIENCE / Physics / Nuclear, SCIENCE / Spectroscopy & Spectrum Analysis, Science / Physics / Atomic & Molecular, Science / Physics / Optics & Light, TECHNOLOGY & ENGINEERING / Microwaves, TECHNOLOGY & ENGINEERING / Nanotechnology & MEMS, TECHNOLOGY & ENGINEERING / Telecommunications, Technology & Engineering / Lasers & Photonics, ANF: Science, Atom- und Molekularphysik, Atomic & Molecular, Atomic & molecular physics, Atomic and molecular physics, Atomic, Molecular and Chemical Physics, Atomphysik, Kernphysik, Chemie, Chemistry, Chemistry - Physical & Theoretical, Electronics engineering, Elektrizität, Magnetismus, Optik, Elektronik, Elektronik, Elektrotechnik, Nachrichtentechnik, Germany, HC, HC/Chemie/Physikalische Chemie, HC/Physik, Astronomie/Atomphysik, Kernphysik, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Maschinenbau, Fertigungstechnik, Hardcover, Softcover, Hardcover, Softcover / Physik, Astronomie/Elektrizität, Magnetismus, Optik, Laser, Laser laser, Laser laser; THz spectroscopy; X-ray techniques; extreme methods in optical measurements; microstructures; phonon techniques; surface differential reflectance spectroscopy; synchrotron radiation; ultrafast spectroscopy; wave propagation in thin films and, Laser laser; THz spectroscopy; X-ray techniques; extreme methods in optical measurements; microstructures; phonon techniques; surface differential reflectance spectroscopy; synchrotron radiation; ultrafast spectroscopy; wave propagation in thin films and, Laser physics, Laserphysik, Lasers & Photonics, Maschinenbau, Fertigungstechnik, Microwaves, Microwaves, RF Engineering and Optical Communications, Nanoscience, Nanotechnologie, Nanotechnology, Nanotechnology & MEMS, Non-Fiction, Nuclear, Optics, Optics & Light, Physical & Theoretical, Physics, Physics - Atomic & Molecular, Physics - Optics & Light, Physics - Quantum Theory, Physik, Astronomie, Physikalische Chemie, SCI/TECH, SCIENCE, SCIENCE / Chemistry / Physical & Theoretical, SCIENCE / Nanoscience, SCIENCE / Physics / Atomic & Molecular, SCIENCE / Physics / Nuclear, SCIENCE / Physics / Optics & Light, SCIENCE / Spectroscopy & Spectrum Analysis, Science/Chemistry - Physical & Theoretical, Science/Math, Science/Nanoscience, Science/Physics - Atomic & Molecular, Science/Physics - Optics & Light, Science/Physics - Quantum Theory, Science/Spectroscopy & Spectrum Analysis, Spectroscopy, Spectroscopy & Spectrum Analysis, Spectrum analysis, spectrochemistry, mass spectrometry, Spektroskopie, Spektrochemie, Massenspektrometrie, TECHNOLOGY & ENGINEERING, TECHNOLOGY & ENGINEERING / Lasers & Photonics, TECHNOLOGY & ENGINEERING / Microwaves, TECHNOLOGY & ENGINEERING / Nanotechnology & MEMS, TECHNOLOGY & ENGINEERING / Optics, TECHNOLOGY & ENGINEERING / Telecommunications, THz spectroscopy, Technik, Technology & Engineering/Lasers & Photonics, Technology & Engineering/Microwaves, Technology & Engineering/Nanotechnology & MEMS, Technology & Engineering/Optics, Technology & Engineering/Telecommunications, Telecommunications, Verstehen, X-ray techniques, extreme methods in optical measurements, microstructures, phonon techniques,

- surface differential reflectance spectroscopy, synchrotron radiation, ultrafast spectroscopy, wave propagation in thin films and, HC/Chemie/Physikalische Chemie, HC/Physik, Astronomie/Atomphysik, Kernphysik, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Maschinenbau, Fertigungstechnik
- **wiązacy:** paperback
 - **jazyk:** english, english, english
 - **waga przedmiotu:** 345 grams
 - **strony:** 240
 - **słowo kluczowe tematu:** Germany, Laser laser, Laser laser; THz spectroscopy; X-ray technicques; extreme methods in optical measurements; microstructures; phonon techniques; surface differential reflectance spectroscopy; synchrotron radiation; ultrafast spectroscopy; wave propagation in thin films and, Laser laser;THz spectroscopy;X-ray technicques;extreme methods in optical measurements;microstructures;phonon techniques;surface differential reflectance spectroscopy;synchrotron radiation;ultrafast spectroscopy;wave propagation in thin films and, Non-Fiction, SCI/TECH, Science/Math, THz spectroscopy, X-ray technicques, extreme methods in optical measurements, microstructures, phonon techniques, surface differential reflectance spectroscopy, wave propagation in thin films and; ultrafast spectroscopy; synchrotron radiation; surface differential reflectance spectroscopy; phonon techniques; microstructures; extreme methods in optical measurements; X-ray technicques; THz spectroscopy; Laser laser
 - **marka:** Springer
 - **kod unspsc:** 55101500
 - **kod podmiotu:** SCI013050, SCI050000, SCI051000, SCI078000, SCI074000, SCI053000, TEC024000, TEC027000, TEC041000, TEC019000, 1655, 1645, 1643, 1684, 1682, PHM, TJF, PHJL, TBN, PNFS
 - **grupa docelowa:** College/University
 - **tom:** 180
 - **numer części:** 9783662507315
 - **kolor:** Red
 - **waga opakowania przedmiotu:** 8.14 pounds
 - **wydanie:** Softcover reprint of the original 1st ed. 2014
 - **numer seryjny:** 180
 - **zewnętrznie przypisany identyfikator produktu:** 3662507315, 9783662507315, 09783662507315
 - **producent:** Springer
 - **tytuł serii:** Springer Series in Optical Sciences
 - **gatunek muzyczny:** Laser physics, Atomic & molecular physics, Spectrum analysis, spectrochemistry, mass spectrometry, Electronics engineering, Nanotechnology, SCIENCE, Physics, Optics & Light, TECHNOLOGY & ENGINEERING, Lasers & Photonics, SCIENCE, Physics, Atomic & Molecular, SCIENCE, Physics, Nuclear, SCIENCE, Chemistry, Physical & Theoretical, SCIENCE, Spectroscopy & Spectrum Analysis, TECHNOLOGY & ENGINEERING, Microwaves, TECHNOLOGY & ENGINEERING, Telecommunications, TECHNOLOGY & ENGINEERING, Nanotechnology & MEMS, SCIENCE, Nanoscience, HC, Physik, Astronomie, Elektrizität, Magnetismus, Optik, HC, Physik, Astronomie, Atomphysik, Kernphysik, HC, Chemie, Physikalische Chemie, HC, Technik, Elektronik, Elektrotechnik, Nachrichtentechnik, HC, Technik, Maschinenbau, Fertigungstechnik, Laser physics, Atomic and molecular physics, Spectrum analysis, spectrochemistry, mass spectrometry, Electronics engineering, Nanotechnology
 - **Data publikacji:** 2016-08-23T00:00:01Z
 - **cena katalogowa uvp:** 106.99
 - **numer wydania:** 1
 - **nazwa przedmiotu:** Frontiers in Optical Methods: Nano-Characterization and Coherent Control (Springer Series in Optical Sciences, Band 180)
 - **data premiery:** 2016-08-23T00:00:01Z
 - **data uruchomienia strony produktu:** 2016-07-27T17:06:22.435Z

Liczba stron	240
Wydanie	Softcover reprint of the original 1st ed. 2016
Język	angielski
Waga	345 gramów